

FORM PTO-1449
INFORMATION DISCLOSURE
STATEMENT BY APPLICANT(S)



Atty Docket No. : 12177/13401
Serial No. : 09/557,672
Inventors : Michael K. BRAND et al.
Filed : April 25, 2000
Group Art Unit : 2128
Examiner : Thai Q. PHAN

U.S. PATENT DOCUMENTS

<u>Examiner Initial</u>	<u>Patent Number</u>	<u>Issue Date</u>	<u>Inventor(s)</u>
<u>T.P.</u>	6,816,813	11-2004	Tan et al.
<u>T.P.</u>	6,684,349	1-2004	Gullo et al.

OTHER DOCUMENTS

Examiner Initial

<u>T.P.</u>	Analog Device's Reliability Handbook. pp. 1-23 out of 88 pages. copyright 2000.
<u>T.P.</u>	Military Standard MIL-STD-690C. March 26, 1993.
<u>T.P.</u>	Hobbs, Gregg. "What HALT and HASS Can Do For Your Products". copyright 1997, Nelson Publishing
<u>T.P.</u>	Wiesling, Paul. "Advance Program 1 st IEEE/CPMT 2-day Workshop on Accelerated Stress Testing, Sept. 7-8, 1995" Aug. 28, 1995.
<u>T.P.</u>	Linear Technology, "Reliability Assurance Program", especially p. 11. Undated. www.linear.com/company/quality/RAPweb.pdf . Printed by Examiner on 12/27/04.

Thai Phan
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4/20/05
DATE CONSIDERED

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T.P.

McLean, Harry. "A Statistical Approach for the Disposition of HALT Issues." Feb. 15, 2001.

T.P.

Prakash, Simon. "The Application of HALT and HASS Principles in a High Volume Manufacturing Environment." Qual. Reliab. Engng. Int., Vol. 14, pp. 385-392, copyright 1998.

T.P.

Confer, R. et al. "Use of Highly Accelerated Life Test (HALT) to Determine Reliability of Multilayer Ceramic Capacitors." Proc. 41st Electronic Components and Technology Conf., 1991. pp. 320-322

T.P.

Gera, A. E. "The Modified Exponentiated Weibull Distribution for Life-Time Modeling." Proc. Annual Reliability and Maintainability Symposium, Jan. 16, 1997. pp. 149-152.

T.P.

Kim, J.S. "A Test of the Exponential MTBF and Comparison of Power Functions of the Random Censoring Case." IEEE Transactions on Reliability. April 1988. pp. 103-107.

T.P.

Mudholkar, G.S. et al. "Exponentiated Weibull Family for Analyzing Bathtub Failure-Rate Data." IEEE Transactions on Reliability. June 1993. pp. 299-302. *(copy not provided by examiner)*

T.P.

Upadhyayula, K. et al. "Guidelines for Physics-of-Failure Based Accelerated Stress Testing." Proc. Annual Reliability and Maintainability Symposium. Jan. 22, 1998. pp. 345-357. *(copy not provided by examiner)*

Thai Phan
EXAMINER SIGNATURE

4/26/05
DATE CONSIDERED

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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T.P.

Scalise, J. "Plastic Encapsulated Microcircuits (PEM) Qualification Testing." 46th Electronic Components and Technology Conference, 1996. May 31, 1996. pp. 392-397.

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